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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/711,085	08/20/2004	Robert J. Gauthier, Jr.	BUR920040079US1	5084	
30678 7	11/30/2005		EXAM	INER	
CONNOLLY BOVE LODGE & HUTZ LLP			PATEL, DHAF	PATEL, DHARTI HARIDAS	
SUITE 800 1990 M STREI	ET NW		ART UNIT	PAPER NUMBER	
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Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)		
	10/711,085	GAUTHIER, JR. 6	ET AL.	(Au)
Office Action Summary	Examiner	Art Unit		
	Dharti H. Patel	2836		
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the c	orrespondence ad	ddress	
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING D. - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period of the provision of the period for reply within the set or extended period for reply will, by statute any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tin will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE	N. hely filed the mailing date of this of D (35 U.S.C. § 133).		
Status				
Responsive to communication(s) filed on <u>20 A</u> This action is FINAL . 2b) ☑ This Since this application is in condition for alloware closed in accordance with the practice under B	s action is non-final. nce except for formal matters, pro		e merits is	
Disposition of Claims				
4) ☐ Claim(s) 1-14 is/are pending in the application 4a) Of the above claim(s) is/are withdra 5) ☐ Claim(s) 11-14 is/are allowed. 6) ☐ Claim(s) 1-2,5-6, 8-10 is/are rejected. 7) ☐ Claim(s) 3-4 and 7 is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or	wn from consideration.			
Application Papers				
9) The specification is objected to by the Examine 10) The drawing(s) filed on 20 August 2004 is/are: Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Examine 11.	a)⊠ accepted or b)□ objected drawing(s) be held in abeyance. Settion is required if the drawing(s) is ob	e 37 CFR 1.85(a). jected to. See 37 C	FR 1.121(d	l).
Priority under 35 U.S.C. § 119				
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Bureat * See the attached detailed Office action for a list	ts have been received. ts have been received in Applicat prity documents have been receive uu (PCT Rule 17.2(a)).	ion No ed in this Nationa	l Stage	
Attachment(s)	A) 🗖 1-4 : 0	(DTO 442)		
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08 Paper No(s)/Mail Date <u>08/20/2004</u>. 	4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal F 6) Other:	ate	O-152)	

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DETAILED ACTION

Specification

1. The disclosure is objected to because of the following informalities:

Page 9, lines 3, 6, "VINV1OUT" should be – "INV1OUT" to be consistent with the drawings.

Page 9, lines 3, 12, "VINV2OUT" should be – "INV2OUT" to be consistent with the drawings.

Appropriate correction is required.

Claim Objections

Claims 1, 8 and 11, line 3, "an FET transistor" should read --- "a FET transistor"
Claim 5 recites the limitation "said resistor" in the second line of the claim. There is insufficient antecedent basis for this limitation in the claim.

Claim 7 is objected to as a claim cannot depend from a higher numbered claim.

Therefore claim 7 will not be further treated.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 1-2, 6, and 8-10 are rejected under 35 U.S.C. 103(a) as being unpatentable over the acknowledged prior art, in view of Wu et al., Patent No. 6,552,886. With respect to claims 1 and 8, applicant's prior art (Fig. 1) teaches a

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basic ESD triggered power clamp circuit which comprises a FET transistor 11 having drain and source connections connected across power supply terminals 10a and 10b of an integrated circuit for clamping the voltage at said terminals to a power supply voltage during an ESD event; an RC timing circuit 13 and 14 connected between the power supply terminals which provides a voltage proportional to an ESD voltage for triggering said FET transistor 11 out of conduction following an ESD event; an inverter circuit having a plurality stages 16, 17, 18 connected between said power supply terminals, said inverter circuit having an input connection connected to receive said RC timing circuit voltage, and having an output connected to said FET transistor gate connection as disclosed in the Specification, Page 6, lines 9-11, 17-20 and Page 7, lines 2-3.

However, the prior art fails to teach or suggest a feedback FET having a drain and source connected in series with one stage of said inverter circuit and said power supply terminals, and having a gate connection connected to said FET gate connection, whereby during an ESD event, said feedback FET provides dynamic feedback preventing said gate connection from latching said FET transistor for clamping the voltage on said terminals into a conducting mode when power supply potential is applied across said terminals.

Wu et al. teaches an active VCC-to-VSS electrostatic discharge protection circuit that comprises a feedback transistor 28 having a drain and source connected in series with one stage 34 of said inverter circuit and said power supply terminals VCC as disclosed in Col. 4, line 61 and Fig. 4.

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Both teachings are related by being electrostatic discharge protection power clamps for suppressing ESD events. Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to combine the teachings of Wu et al., which teaches a feedback transistor, into the power clamp circuit of the applicant's acknowledged prior art to protect the internal power supplies of an integrated circuit. Also, the feedback transistor increases a divided voltage required to turn on the control gate of the clamping transistor, which in turn reduces latch up events.

With respect to claim 2, Wu et al. teaches an active VCC-to-VSS ESD protection circuit that comprises an inverter circuit comprising first 32, second 34, and third 38 pairs of serially connected inverters implemented as FET transistors (Fig. 3) connected across said power supply terminals VCC and VSS, said pairs of transistors 32, 34, 38 having common gate connections, said first pair of transistors 32 having gate connections connected to said RC timing circuit 24 and 25, said second pair of transistors 34 having gate connections connected to the serial connection of said first pair of transistors 32, and said third pair of transistors 38 having gate connections connected to the serial connection of said second pair of transistors 34, said feedback FET 28 being connected in series with said second pairs of serially connected transistors 34, said third pair of transistors 38 serial connection connected to said FET 30 gate connection as disclosed in Fig. 3 and Fig. 4.

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With respect to claim 5, it would have been obvious to those skilled in the art at the time the invention was made to add a FET based resistor for forming an RC circuit comprised of a resistor in combination with the parasitic capacitance of FET to enhance response during transient ESD events.

With respect to claim 6, Wu et al. teaches a feedback transistor 28 that is connected in series with a pull up transistor of said inverter circuit stage 34 as disclosed in Fig. 4.

With respect to claim 9, Wu et al. teaches a polarity which is reversed from the claimed N-MOSFET transistor as a feedback transistor and P-MOSFET transistor as a FET transistor. It would have been obvious to those skilled in the art at the time the invention was made to reverse the polarity of the transistor devices to address the expected polarity of an ESD event or to address polarity considerations related to power supply connections.

With respect to claim 10, Wu et al. teaches an ESD protection circuit wherein the FET transistor 30 is an N-MOSFET transistor and the feedback transistor 28 is a P-MOSFET transistor as disclosed in Fig. 4.

Allowable Subject Matter

Claims 3-4 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The following is an examiner's statement of reasons for indicating allowance of claim 3: Wu et al. teaches an ESD protection circuit that comprises

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an inverter circuit, an RC circuit, and a feedback transistor but does not disclose a second feedback transistor for supplying a feedback signal to said inverter circuit from said FET gate connection for reducing the power up current drawn by said FET during power up. This feature in combination with the rest of the claim limitations is not anticipated or rendered obvious by the prior art of record.

5. Claims 11-14 are allowed. The following is an examiner's statement of reasons for indicating allowance of claim 11: Wu et al. teaches an ESD protection circuit that comprises a FET transistor, an RC timing circuit, an inverter circuit connected across power supply terminals VCC and VSS, and a first feedback transistor but does not disclose a second feedback transistor having source and drain connections connected across said serial connection of said first transistor and said pull-up transistor, said second feedback transistor reducing power consumption during a power up of said power supply voltage.

This feature in combination with the rest of the claim limitations is not anticipated or rendered obvious by the prior art of record.

6. Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Dharti H. Patel whose telephone number is 571-272-8659. The examiner can normally be reached on 8:30am - 5pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Brian Sircus can be reached on 571-272-2800, Ext. 36. The fax

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phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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DHP 11/04/2005

> PHUONG T. VU PRIMARY EXAMINER